Abstracts

An Improved Interferometric Polarization Analyzer for Measuring the Microwave Magneto-Kerr Effect in Semiconductors

R.J. Vernon and T.A. Dorschner. "An Improved Interferometric Polarization Analyzer for Measuring the Microwave Magneto-Kerr Effect in Semiconductors." 1971 Transactions on Microwave Theory and Techniques 19.3 (Mar. 1971 [T-MTT]): 287-294.

An interferometric polarization analyzer for measuring the microwave magneto-Kerr effect in semiconductors is described and analyzed, and compared with earlier systems used for the same purpose. The system described utilizes a 4-port waveguide junction referred to as a dual-mode transducer (DMT). This system has important advantages over systems previously used to measure the microwave magneto-Kerr effect. Preliminary data taken with the system are presented and sources of error discussed.

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